## Applicant(s)/Patent Under Application/Control No. Reexamination 09/843,354 LEE, GYE-CHOOL Notice of References Cited Examiner Art Unit Page 1 of 1 Hong Cho 2662 **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name MM-YYYY Country Code-Number-Kind Code US-6,345,053 02-2002 Jeon, Young Ki 370/441 455/445 US-6,535,732 03-2003 McIntosh et al. В US-6,729,929 05-2004 Sayers et al. 455/446 C 12-2002 Leung, Kent K. 370/338 US-6,501,746 D 370/349 08-2004 Vilander et al. Ε US-6,771,635 F US-5,493,286 02-1996 Grube et al. 340/7.25 G US-6,766,168 07-2004 Lim, Byung Keun 455/435.1 02-2003 Lindsay et al. 370/280 US-6,515,970 US-US-J US-Κ US-М US-FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν o Ρ Q R S Т NON-PATENT DOCUMENTS Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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## Applicant(s)/Patent Under Application/Control No. Reexamination 09/843,354 LEE, GYE-CHOOL Notice of References Cited Examiner Art Unit Page 1 of 1 Hong Cho 2662 **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification MM-YYYY Country Code-Number-Kind Code Beeson et al. 01-1994 340/7.24 A US-5,278,890 370/337 US-5,513,183 04-1996 Kay et al. В 370/280 US-6,515,970 02-2003 Lindsay et al. С US-6,766,168 07-2004 Lim, Byung Keun 455/435.1 D 02-2002 370/441 US-6,345,053 Jeon, Young Ki E F US-6,442,384 08-2002 Shah et al. 455/423 US-G USн US-1 US-J US-K US-US-М FOREIGN PATENT DOCUMENTS Document Number Country Name Classification Country Code-Number-Kind Code MM-YYYY N 0 Ρ Q R s Т NON-PATERT DOCUMENTS Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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